

	<p>DCU BIAS TEST PLAN</p>	 <p>SAP-SPIRE- FP-0066-02 Issue : 0.-1 Date : 18/02/03</p>
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## HERSCHEL/SPIRE

### DETECTOR CONTROL UNIT BIAS TEST PLAN

BIAS BOARD Number:1

	Function	Name	Date	Visa
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## DOCUMENT STATUS and CHANGE RECORD

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## 1 INTRODUCTION

### 1.1 PURPOSE

The purpose of this document is to detail the tests that have been performed on the BIAS boards. This document follows a specific order: first the success criteria are given, followed by the testing parameters and finally whether the test was successful or not.

### 1.2 SCOPE

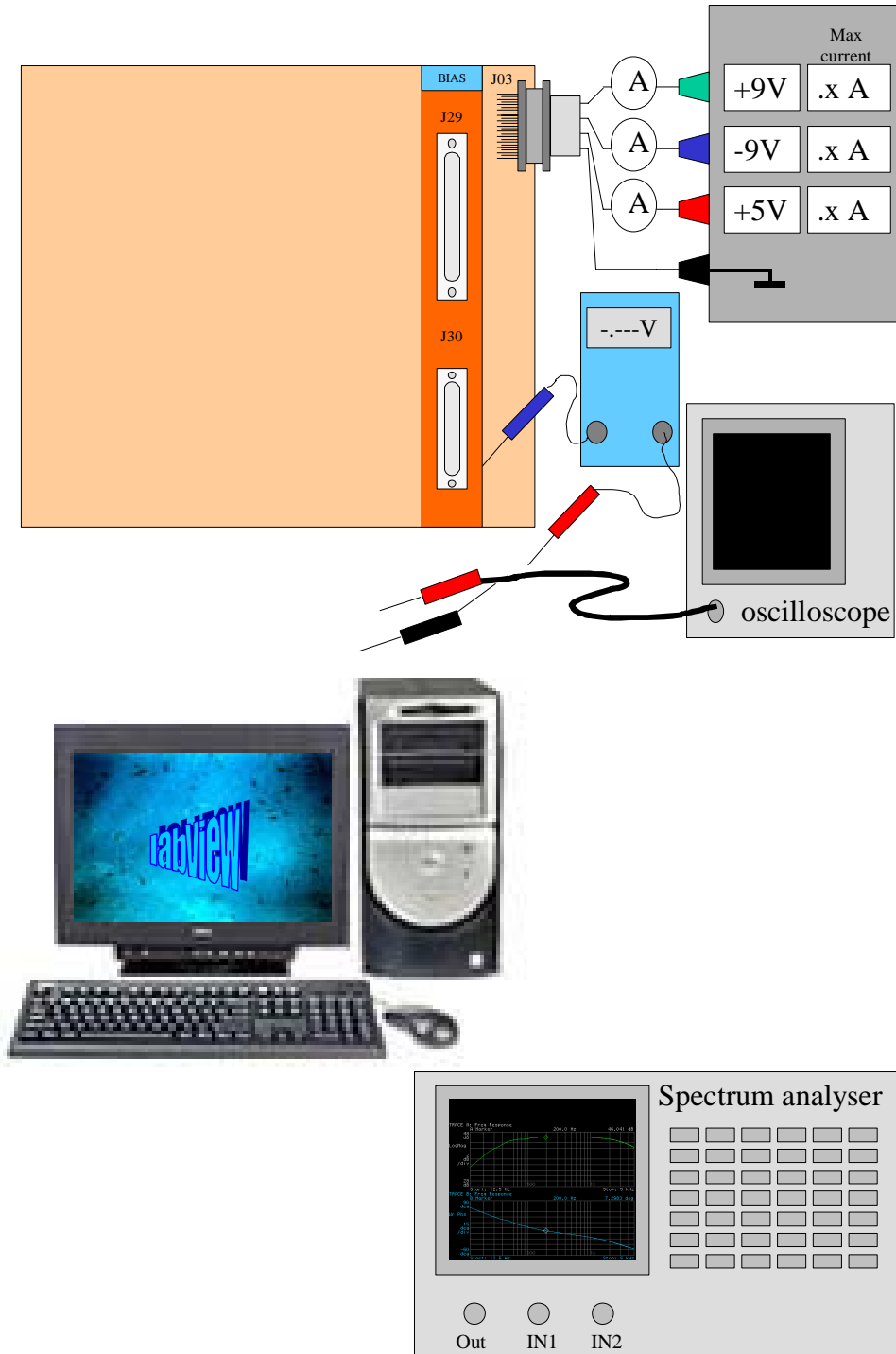
### 1.3 APPLICABLE DOCUMENTS

### 1.4 REFERENCE DOCUMENTS

- DETECTOR SUBSYSTEM SPECIFICATION DOCUMENT : FIST-SPI-PRJ-000103
- DRCU SUBSYSTEM SPECIFICATION DOCUMENT : SAp-SPIRE-CCa-25-00

## 2 GENERAL DESCRIPTION

### 2.1 OVERVIEW



Picture 2-1: overview

### 3 TEST EQUIPEMENTS

- |                                    |                      |
|------------------------------------|----------------------|
| - DUAL OUTPUT DC POWER SUPPLY      | HP E3620A 0-25V 0-1A |
| - DIGITAL OSCILLOSCOPE             | TEKTRONIX 2230       |
| - MULTIMETER                       | WAVETEK              |
| -2 CHANNEL NETWORK SIGNAL ANALYZER | SRS SR780            |

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## 4 DCU QM1 ELECTRICAL TESTS

### 4.1 BIAS test

#### 4.1.1 Visual test

Test number	Test	Test Date	Result	Corrections	Test Status OK/NOK
BIAS_ 1	Check that no components missing and all the component are in the good way.	1/7/02	R172 missing	Add 1ohm resistor For R172	OK
BIAS_ 2	Check that there isn't any visible short circuit	1/7/02	None		OK
BIAS_ 1 BIS	Check that no components missing and all the component are in the good way.	1/7/02	Design error missing the temperature sensor. Error on the footy print of the 37 pins connector S2	<b>NON CONFORMANCE</b>	NOK

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#### 4.1.2 Test with power supplies

##### 4.1.2.1 Test

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_ 3	Switch on the lab power Check there is any short circuit.	2/7/02			OK
BIAS_ 4	Measure the static current on +9V (without external loads)	2/7/02	For photometer: 47.8mA For spectrometer:30.6mA		OK
BIAS_ 5	Measure the static current on -9V (without external loads)	2/7/02	For photometer: 36.6mA For spectrometer:20.4mA		OK

BIAS_ 6.1	Measure the static current on +9V (loaded)	9/7/02	For photometer:114.8 mA For spectrometer:47.7mA		OK
BIAS_ 7.1	Measure the static current on -9V (loaded)	9/7/02	For photometer: 137.6mA For spectrometer:44.4mA		OK



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Additional test

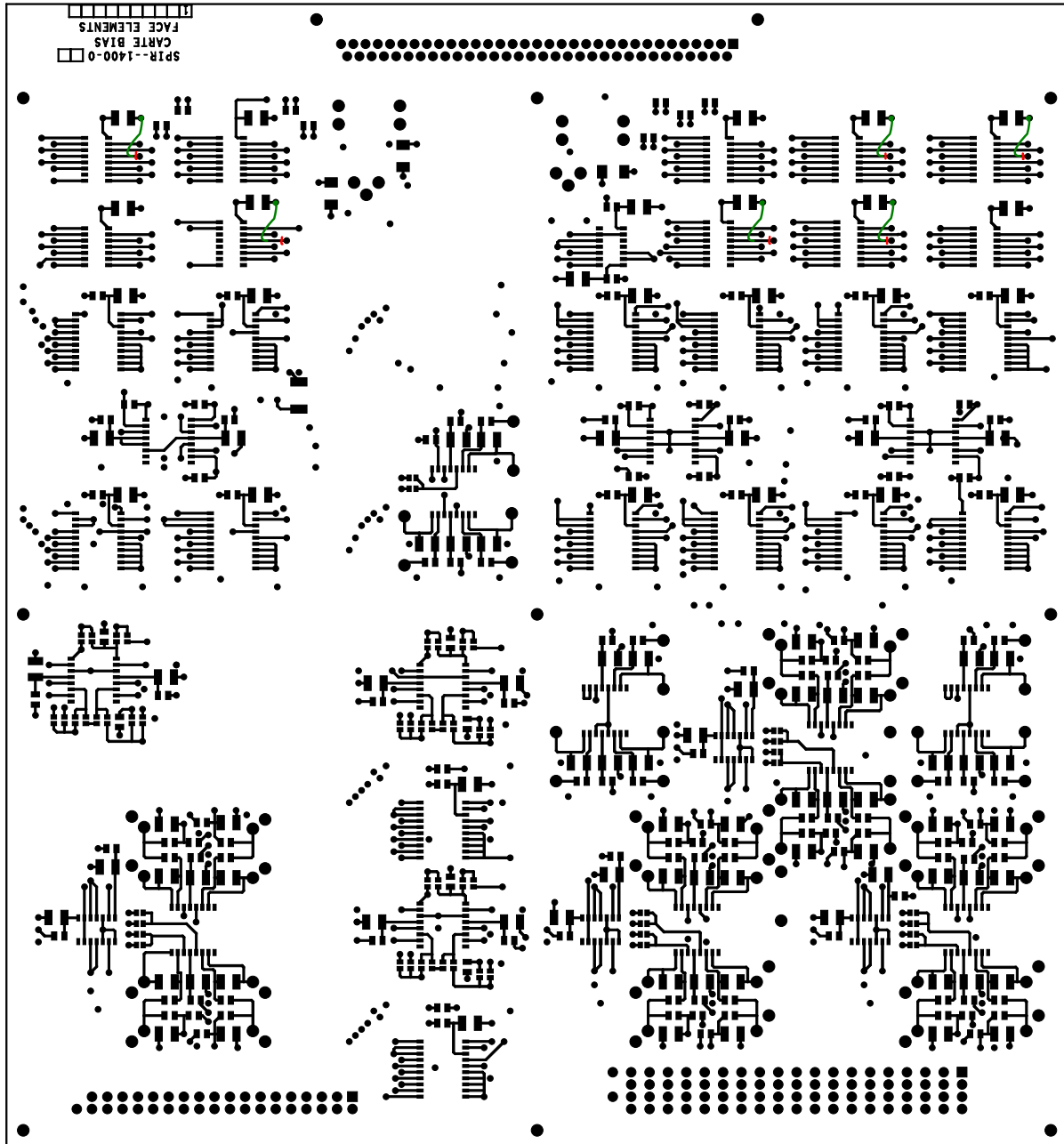
Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_3.1	Measure of P9V_P	2/7/02	8.91V		OK
BIAS_3.2	Measure of P9V_P1	2/7/02	8.86V		OK
BIAS_3.3	Measure of N9V_P	2/7/02	-9.23V		OK
BIAS_3.4	Measure of N9V_P1	2/7/02	-9.18V		OK
BIAS_3.5	Measure of P5_P	2/7/02	6.3V NOK <b>NON CONFORMANCE</b>	The 15k R262 is replaced by a 1k And the 5k R263 is replaced by three 1k in parallel  Then P5_P = 5.03V	OK
BIAS_3.6	Measure of P9V_S	2/7/02	8.91V		OK
BIAS_3.7	Measure of P9V_S1	2/7/02	8.88V		OK
BIAS_3.8	Measure of N9V_S	2/7/02	-9.23V		OK
BIAS_3.9	Measure of N9V_S1	2/7/02	-9.2V		OK
BIAS_3.10	Measure of P5_S	2/7/02	5.6V NOK <b>NON CONFORMANCE</b>	The 15k R177 is replaced by a 1k And the 5k R178 is replaced by three 1k in parallel  Then P5_P = 5.03V	OK
BIAS_3.11	Power supply for each actif components	2/7/02			OK
BIAS_3.12	Measure of REF5V_P Measure of REF5V_S	2/7/02	5V		OK

**NON CONFORMANCE:**

Corrections: connect the pin 13 of all 74HC595 to GND instead of P5V.

Red lines = cut (6)

Green lines = new connections (6)



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#### 4.1.2.1.1 Jfet Power VDD

Switch ON All JFET power VDD:

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_8	Check with the voltmeter that we have 2.5V on: -All VDD JFET output	3/7/2002 & 9/7/2002	2.45V (with 500ohm resitor between VDD and GND) 2.49V with no load		OK
BIAS_9	Load ALL VDD with 500ohm between VDD and GND. And check with an oscilloscope that switching off and on the JFET power doesn't generate any overshoot.	9/7/2002	From 2.45 to 0v in 200µs From 0 to 2.45v in 200µs  With no overshoot		OK
BIAS_10	Check with the spectrometer that the noise on VDD is <0.3µV/rtHz (2 to 800Hz)	10/7/2002	<200n V/rtHz		OK

Switch OFF All JFET power VDD:

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_11 bis	Check with the voltmeter that we have 0V on: -All VDD JFET output	3/7/2002 & 9/7/2002	0,000V (with 500ohm resitor between VDD and GND) 0.000V with no load		OK

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#### 4.1.2.1.2 Jfet Power VSS and Heater

Load all “VSS DAC” and “heater DAC” with “FF”

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_12	Check with the voltmeter that we have -5V on: All VSS and Nhearter output	3/7/2002 & 9/7/2002	-4.96V (with 1K resitor between VSS and GND) (5.01V with no load) NOK for VSS_TC	(VSS_TC) add a connection between pin 20 of U52 and pin 16 of U17 connect pin 19 of U52 to REF5V_P instead of SINE_P 3/7/2002	OK
BIAS_13	Load ALL VSS and Nhearter outputs with 1000ohm between VSS and GND. And check with an oscilloscope that switching off and on the JFET power doesn't generate any overshoot.	9/7/2002	From -5 to 0V in 300µs From 0 to -5V in 300µs  With no overshoot		OK
BIAS_14	Check with the spectrometer that the noise on VSS <1µV/rtHz (2 to 800Hz)	10/7/2002	250 nV/rtHz		OK

Load all “VSS DAC” and “heater DAC” with “AA”

BIAS_15	Check with the voltmeter that we have -3.33V on: All VSS and Nhearter output	3/7/2002 & 9/7/2002	-1.66V (with 1K resitor between VSS and GND) -1.67V with no load	Bit rotation from lsb to msb (check vhdl)	NOK
		11/7/2002		afterVhdl correction	OK

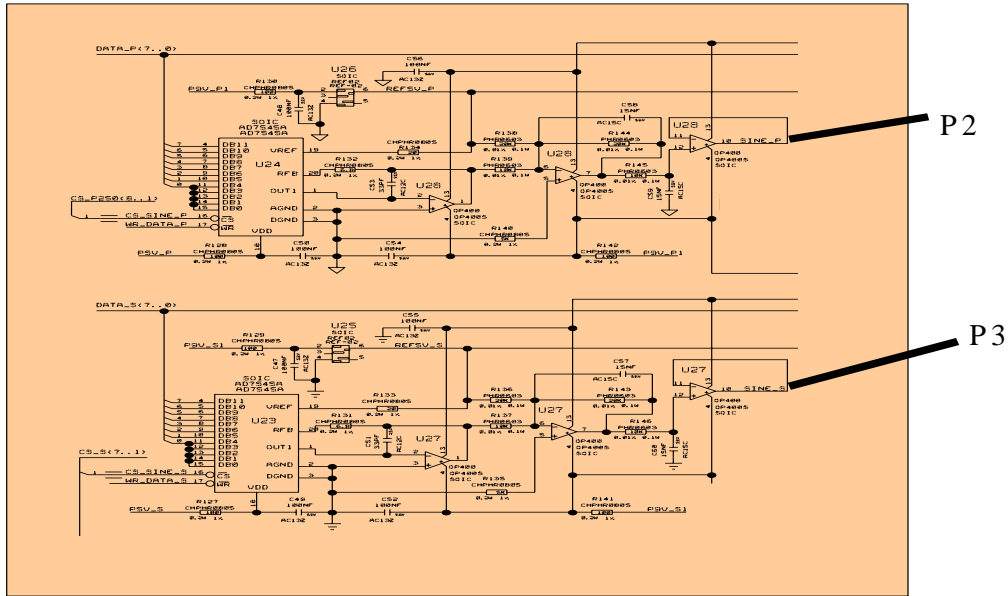
Load all “VSS DAC” and “heater DAC” with “55”

BIAS_16	Check with the voltmeter that we have -1.66V on: All VSS and Nhearter output	3/7/2002 & 9/7/2002	-3.29V (with 1K resitor between VSS and GND) 3.33V with no load	Bit rotation from lsb to msb (check vhdl) Vhdl correction 11/7/2002	NOK
		11/7/2002		afterVhdl correction	OK

Load all “VSS DAC” and “heater DAC” with “00”

BIAS_17 bis	Check with the voltmeter that we have 0V on: All VSS and Nhearter output		0,000V (with 1K resitor between VSS and GND) 0,000V with no load		OK
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#### 4.1.2.1.3 Sine DAC



Load all “sine DAC” with “FE”

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_18	Check with the voltmeter that we have 5V on: - Test point P2 and P3	5/7/2002	0v (7F → 4.94V)	Bit rotation from lsb to msb (check vhd1)	NOK
		11/7/2002		afterVhdl correction	OK

Load all “sine DAC” with “AA”

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_18	Check with the voltmeter that we have 1.66V on: - Test point P2 and P3	5/7/2002	-1.64v	Bit rotation from lsb to msb (check vhd1)	NOK
		11/7/2002		afterVhdl correction	OK

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Load all “ sine DAC” with “55”

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_18	Check with the voltmeter that we have -1.66V on: - Test point P2 and P3	5/7/2002	1.64v	Bit rotation from lsb to msb (check vhd1) Vhdl correction 11/7/2002	NOK
		11/7/2002		afterVhdl correction	OK

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#### 4.1.2.1.4 ATT DAC

Load all “ ATT DAC” with “FF” and all “ sine DAC” with “FE”

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_19	Check with the voltmeter that we have 200mV Between each couple PBIAS and NBIAS	5/7/2002	187.4mV (sine DAC with 7F)	Bit rotation from lsb to msb (check vhdl)	OK

Load all “ sine DAC” with “AA” and all “ sine DAC” with “FE”

BIAS_19	Check with the voltmeter that we have 133mV Between each couple PBIAS and NBIAS	5/7/2002	62.9mV	Bit rotation from lsb to msb (check vhdl)	OK
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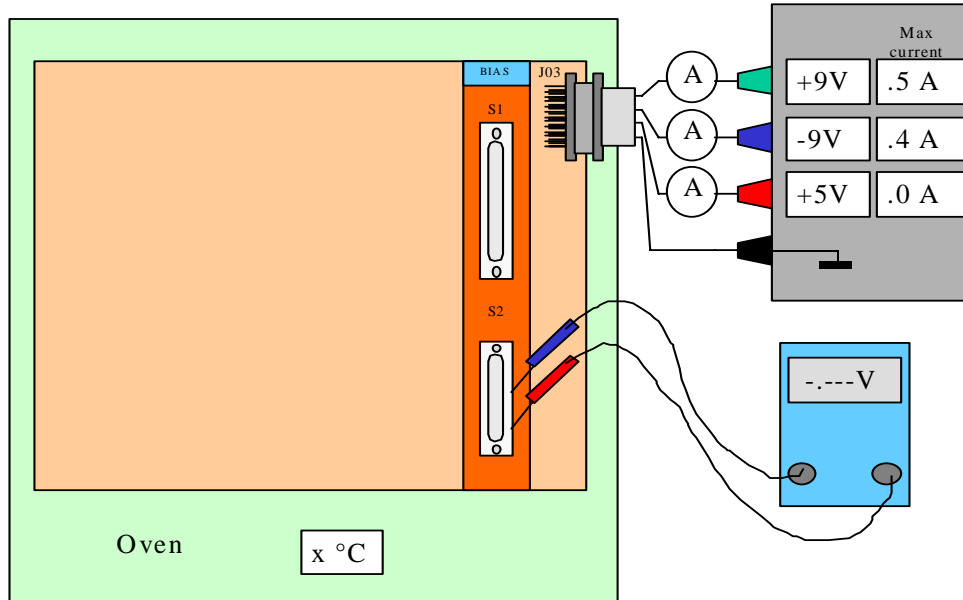
Load all “ sine DAC” with “55” and all “ sine DAC” with “FE”

BIAS_19	Check with the voltmeter that we have 66mV Between each couple PBIAS and NBIAS	5/7/2002	124.5mV	Bit rotation from lsb to msb (check vhdl)	OK
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Load all “ ATT DAC” with “FF” and run the sine mode

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_20	Measure all the output signal harmonic FOR a frequency of 50Hz (186)	12/7/2002	50Hz: -24dBVrms 150Hz: -85dBVrms 12,8kHz: -90dBVrms		
BIAS_20	Measure all the output signal harmonic FOR a frequency of 200Hz (61)		200Hz: -24dBVrms 600Hz: -90dBVrms 51,2kHz: -85dBVrms		
BIAS_20	Measure all the output signal harmonic FOR a frequency of 300Hz (41)		300Hz: -25,6dBVrms 900Hz: -95dBVrms 76,8kHz: -85dBVrms		

4.1.2.1.5 BIAS and JFET power TEMPERATURE STABILITE



Load all DAC with "7F"

Measurement at 0°C

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_21	For VDD Measure with a voltmeter all the output voltage				
BIAS_21	For VSS Measure with a voltmeter all the output voltage				
BIAS_21	For HEATER Measure with a voltmeter all the output voltage				
BIAS_21	For BIAS Measure with a voltmeter all the output voltage				



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Measurement at 20°C

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_21	For VDD Measure with a voltmeter all the output voltage				
BIAS_21	For VSS Measure with a voltmeter all the output voltage				
BIAS_21	For HEATER Measure with a voltmeter all the output voltage				
BIAS_21	For BIAS Measure with a voltmeter all the output voltage				

Measurement at 40°C

Test number	Test	Test check Date	Check Result	Corrections	Test Status OK/NOK
BIAS_21	For VDD Measure with a voltmeter all the output voltage				
BIAS_21	For VSS Measure with a voltmeter all the output voltage				
BIAS_21	For HEATER Measure with a voltmeter all the output voltage				
BIAS_21	For BIAS Measure with a voltmeter all the output voltage				

## 5 TRACEABILITY MATRIX

Requirement ID	Description	Test
BDA-DRCU-05	The DRCU is to provide 5 BDA bias signals, adjustable from 0 to 200 mV <sub>rms</sub> , and 1 bias signal for temperature readout, adjustable from 0 to 500 mV <sub>rms</sub> . The temperature readout biases are to be divided from a common oscillator. Each bias shall be adjustable with 8-bit precision. The frequency of each bias shall be adjustable between 50 and 300 Hz, with a precision of 5 Hz.	BIAS_ 18 BIAS_ 19 BIAS_ 20
BDA-DRCU-06	The DRCU will provide 15 commandable JFET source voltages with 256 levels. The range of Vss is from 0 V to -5 V.	BIAS_ 12 BIAS_ 15 BIAS_ 16
BDA-DRCU-07	Vdd is to be adjustable from 1.5 to 4 V.	BIAS_ 8
BDA-DRCU-08	Vdd and Vss lines individually must source 1 mA to 5 mA. Noise on Vss < 1 μV/√Hz, and noise on Vdd < 0.3 μV/√Hz within modulated band (50 – 300 Hz), measured at the DRCU DxMA connector.	BIAS_ 10 BIAS_ 14
BDA-DRCU-09	Each of the 15 Vdd and Vss supplies must be commandable ON/OFF for spectrometer and photometer independently, without overshoot. Each Vdd and Vss pair are turned on and off together.	BIAS_ 9 BIAS_ 13
BDA-DRCU-10	The DRCU will provide 2 double-wired JFET heater lines with adjustable amplitude and duration. The supplies must be able to provide 5 V and 25 mA (photometer), 3 V and 10 mA (spectrometer). Each heater line is commandable ON/OFF, with a minimum duration of 10 s.	BIAS_ 12